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IN THE SPECIFICATION:

Page 14, second full paragraph, please amend as follows:

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*A1* In an advanced integrated circuit, however, the number of test patterns executed is limited due to a limitation on an a detection time associated with costs. Thus, it is important to promptly and efficiently detect a defect in the integrated circuit. Accordingly, it is necessary to determine the probability of detecting faults in the integrated circuit using certain test patterns, that is, to evaluate a fault coverage.

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